Supplementary Information

Probing Composition Distributions in Nanoalloy Catalysts with Correlative Electron Microscopy

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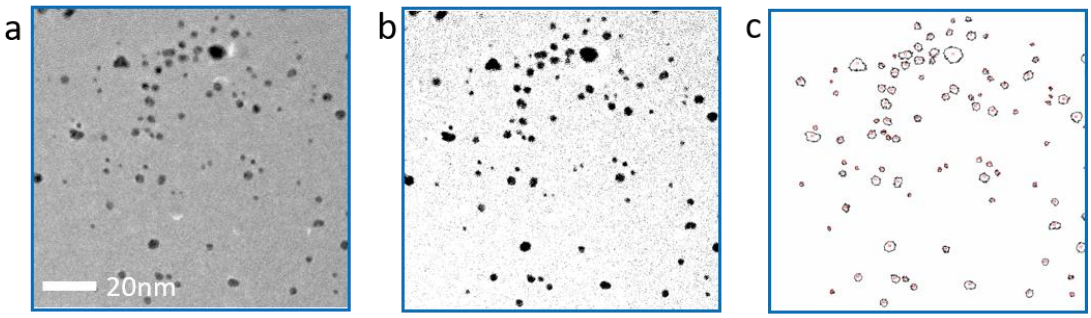
Table S1. Composition of the AuPd nanoalloys as determined ed by ICP-AES.

Catalyst	**Pd content** **wt%** M_{Pd}	Relative error %	**Au content** **wt%** M_{Au}	Relative error %	**Pd:Au wt ratio**
1wt%AuPd/TiO_2(PVP)	**0.39**	2.5	**0.4**	2.5	**0.98**
1wt%AuPd/TiO_2(PVA)	**0.37**	5%	**0.35**	9%	**1.05**

[a] The sample for ICP-AES was obtained by digesting the catalysts in *aqua regia*. The solution was then filtered and diluted down to a metal concentration of about 10ppm before being tested.



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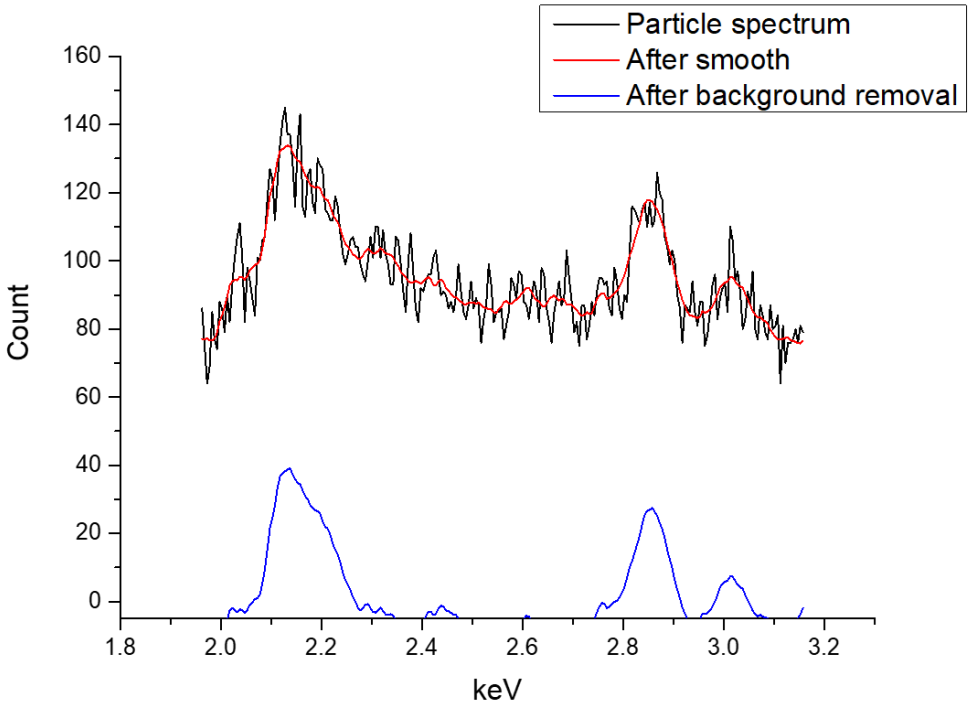

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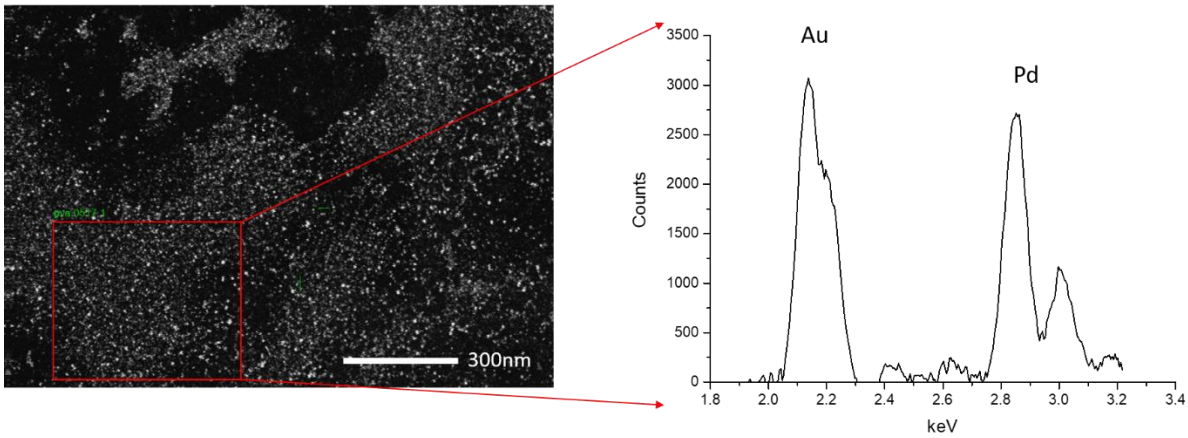

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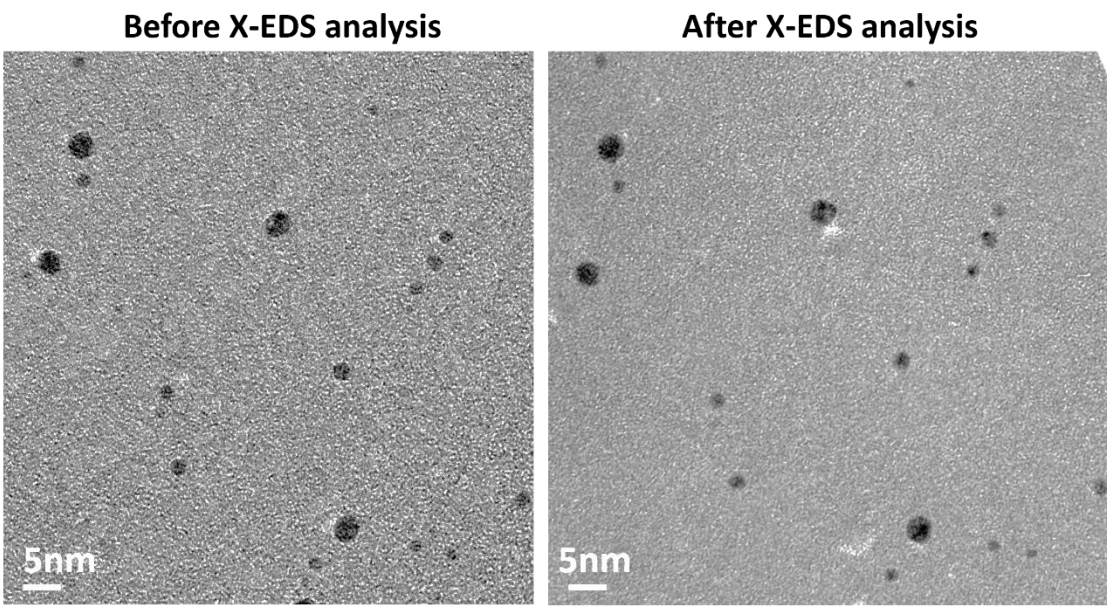

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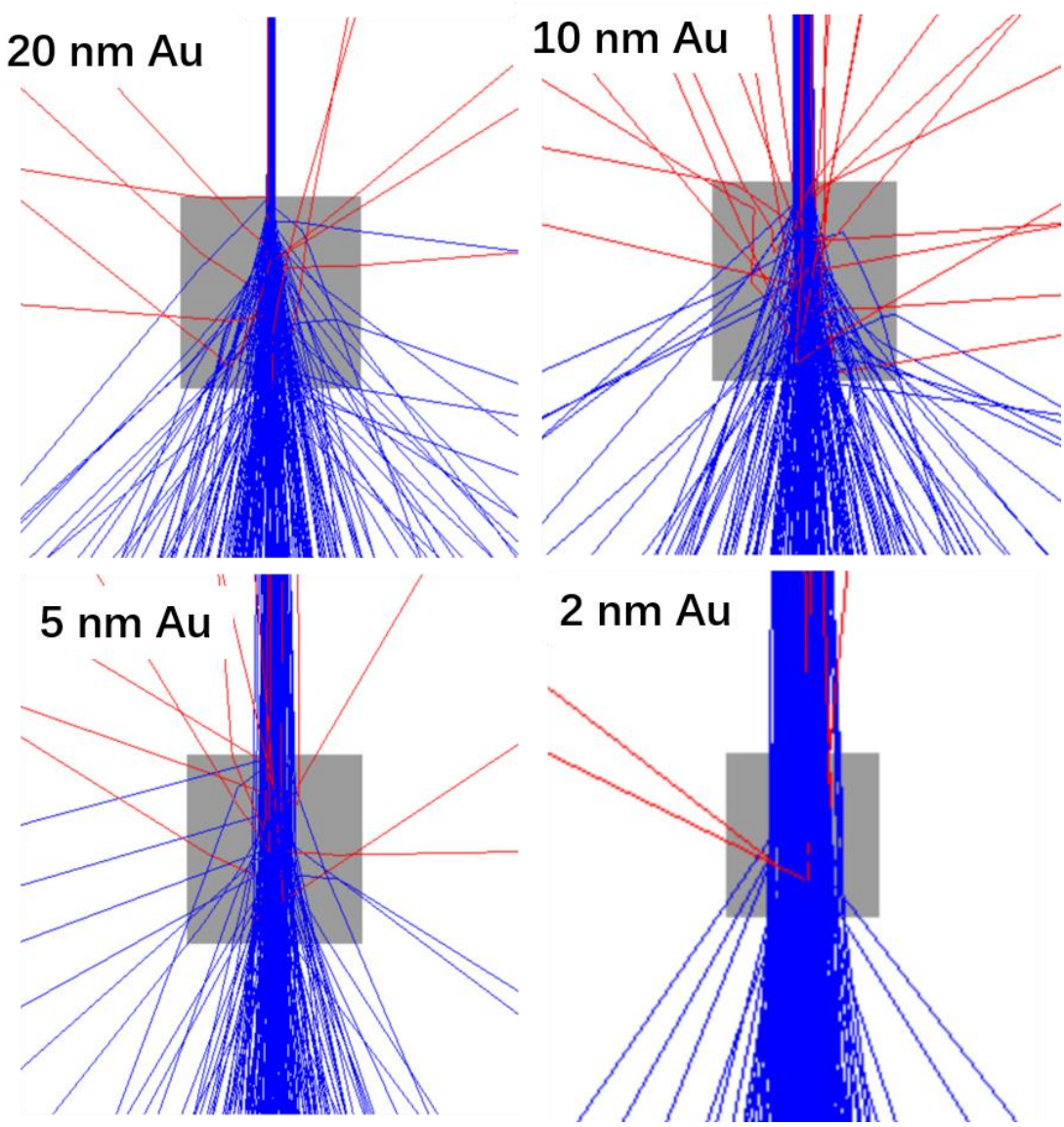

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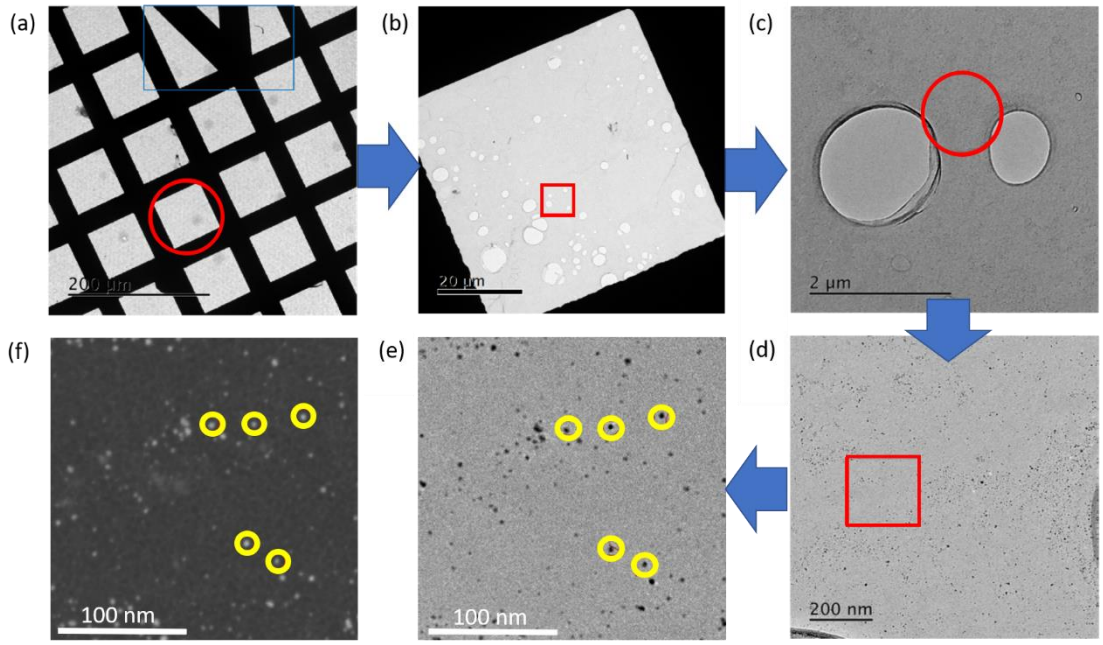

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